

Notice of References Cited	Application/Control No. 09/943,860	Applicant(s)/Patent Under Examination NIHEI ET AL.	
	Examiner <i>QML 9.03</i> Quyen P. Leung	Art Unit 2828	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5018155	05-1991	Miyairi	372/31
	B	US-			
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	D	US-			
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FOREIGN PATENT DOCUMENTS

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